

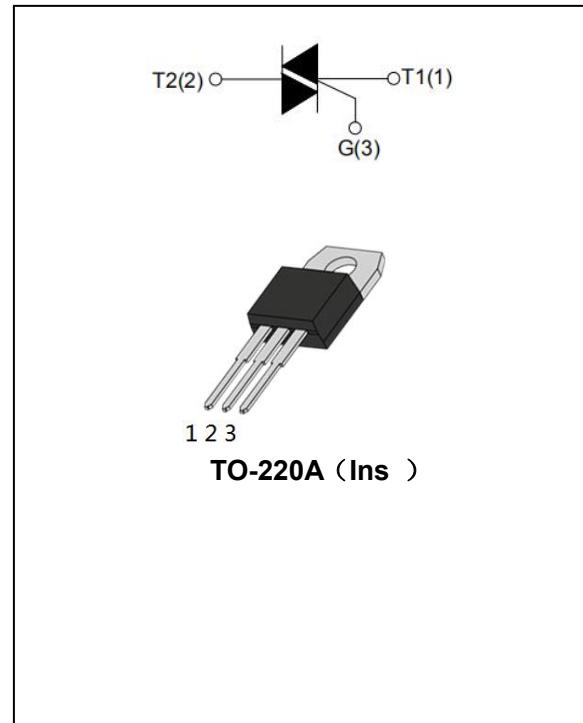


# Jiangsu Weida Semiconductor Co., Ltd.

## T25\*\*H 25A High Junction Temperature Triacs

### DESCRIPTION:

T25\*\*H triacs of high junction temperature with high dv/dt rate with strong resistance to electromagnetic interference provide high ability to withstand the shock loading of large current. They are especially recommended for use on inductive load and high environment temperature condition.



### MAIN FEATURES:

symbol	value	unit
$I_{T(RMS)}$	25.0	A
$V_{DRM}/V_{RRM}$	600/800	V

### ABSOLUTE MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Storage junction temperature range	$T_{stg}$	-40~150	°C
Operating junction temperature range	$T_j$	-40~150	°C
Repetitive peak off-state voltage ( $T_j=25^\circ\text{C}$ )	$V_{DRM}$	600/800	V
Repetitive peak reverse voltage ( $T_j=25^\circ\text{C}$ )	$V_{RRM}$	600/800	V
RMS on-state current	$I_{T(RMS)}$	25	A
Non repetitive surge peak on-state current (full cycle, $F=50\text{Hz}$ )	$I_{TSM}$	250	A
$I^2t$ value for fusing ( $t_p=10\text{ms}$ )	$I^2t$	335	$\text{A}^2\text{s}$
Critical rate of rise of on-state current ( $I_G=2\times I_{GT}$ )	$dI/dt$	50	$\text{A}/\mu\text{s}$
Peak gate current	$I_{GM}$	4	A
Average gate power dissipation	$P_{G(AV)}$	1	W



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Peak gate power	P <sub>GM</sub>	10	W
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### ELECTRICAL CHARACTERISTICS ( $T_j=25^\circ\text{C}$ unless otherwise specified)

Parameter	Test Condition	Quadrant		Value			Unit	
				T2510	T2535	T2550		
I <sub>GT</sub>	V <sub>D</sub> =12V, R <sub>L</sub> =33Ω	I - II -III	MAX	10	35	50	mA	
V <sub>GT</sub>				1.5			V	
V <sub>GD</sub>	V <sub>D</sub> =V <sub>DRM</sub>		MIN	0.2			V	
I <sub>H</sub>	I <sub>T</sub> =100mA		MAX	10	45	60	mA	
I <sub>L</sub>	I <sub>G</sub> =1.2I <sub>GT</sub>	I - III	MAX	20	50	70	mA	
		II		35	70	90		
dV/dt	V <sub>D</sub> =2/3V <sub>DRM</sub> T <sub>j</sub> =150°C Gate open		MIN	500	1000	1500	V/μs	

### STATIC CHARACTERISTICS

Symbol	Test Condition			Value	Unit
V <sub>TM</sub>	I <sub>TM</sub> =35A t <sub>p</sub> =380μs	T <sub>j</sub> =25°C	MAX	1.5	V
I <sub>DRM</sub> I <sub>RRM</sub>	V <sub>DRM</sub> = V <sub>RRM</sub>	T <sub>j</sub> =25°C	MAX	10	μA
		T <sub>j</sub> =125°C		3	mA

### THERMAL RESISTANCES

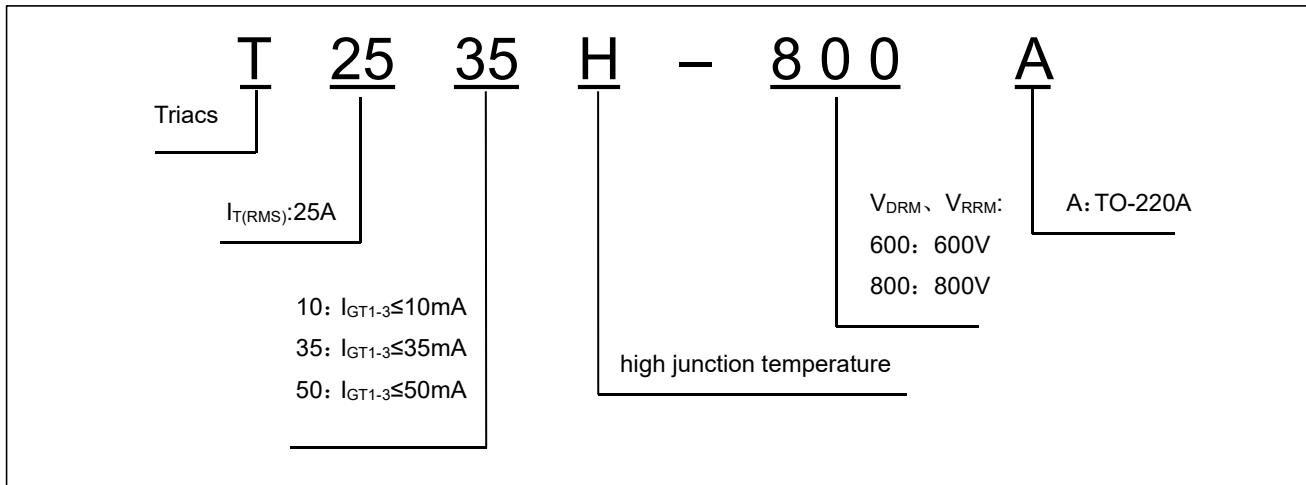
Symbol	Test Condition		Value	Unit
R <sub>th(j-c)</sub>	junction to case(AC)	TO-220A(Ins)	1.7	°C/W



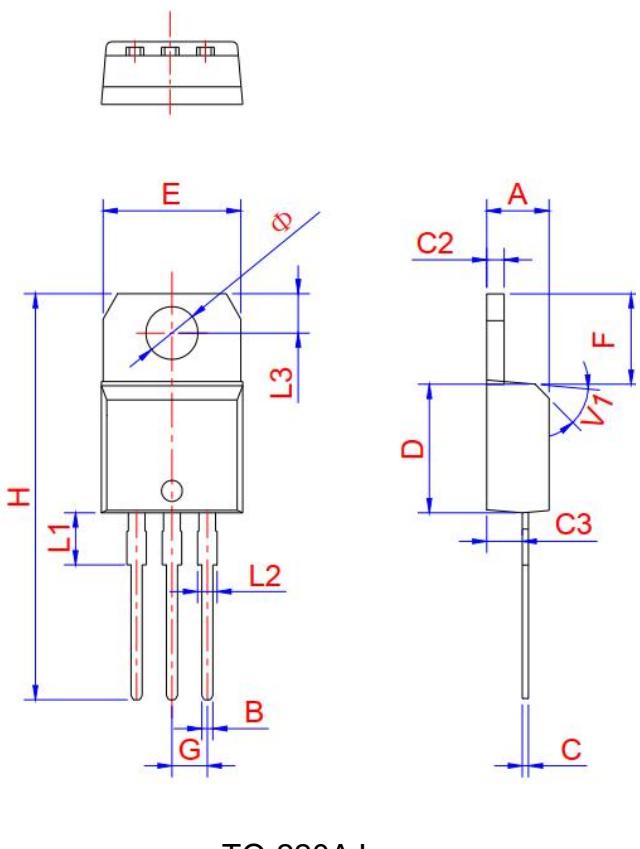
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### ORDERING INFORMATION



### PACKAGE MECHANICAL DATA

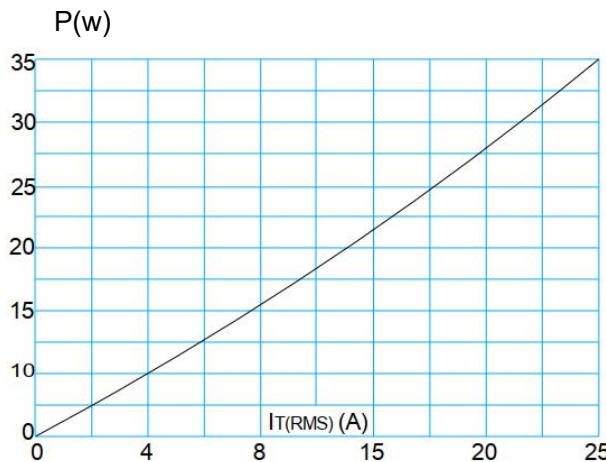


Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	4.4	4.47	4.6	0.173	0.176	0.181
B	0.61		0.88	0.024		0.035
C	0.46	0.50	0.7	0.018	0.02	0.028
C2	1.21	1.27	1.32	0.048	0.050	0.052
C3	2.4		2.72	0.094		0.107
D	8.6		9.7	0.339		0.382
E	9.8		10.4	0.386		0.409
F	6.55		6.95	0.258		0.274
G		2.54			0.1	
H	28		29.8	1.102		1.173
L1		3.75			0.148	
L2	1.14		1.7	0.045		0.067
L3	2.65		2.95	0.104		0.116
V1		45°			45°	
Φ	3.7	3.75	3.8	0.145	0.147	0.149

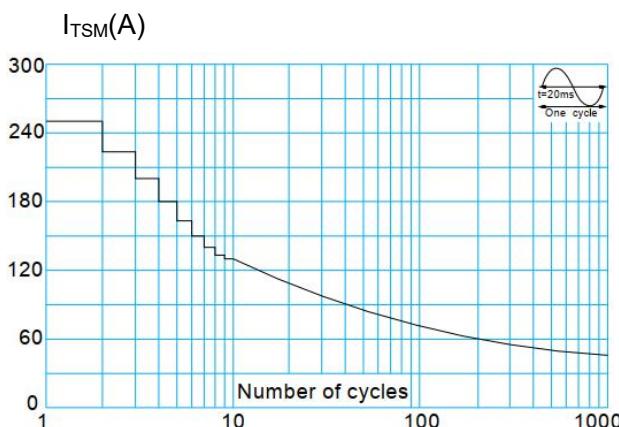
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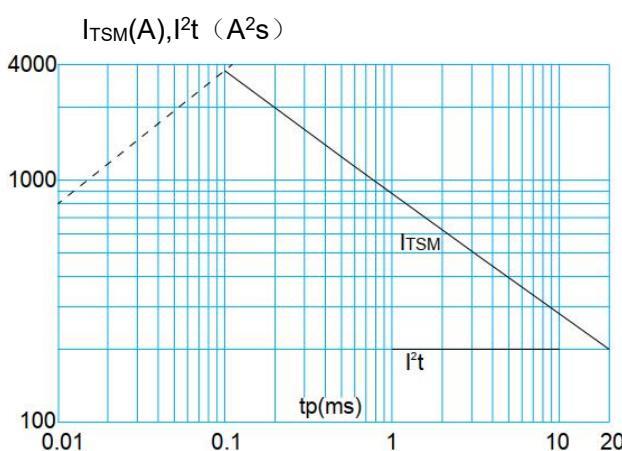
**FIG.1:** Maximum power dissipation versus RMS on-state current



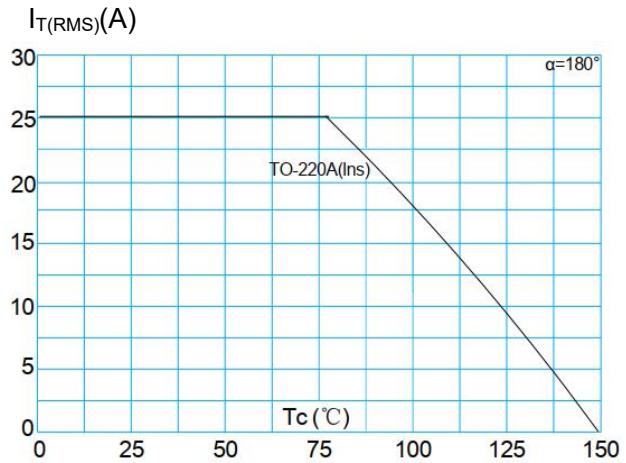
**FIG.3:** Surge peak on-state current versus number of cycles



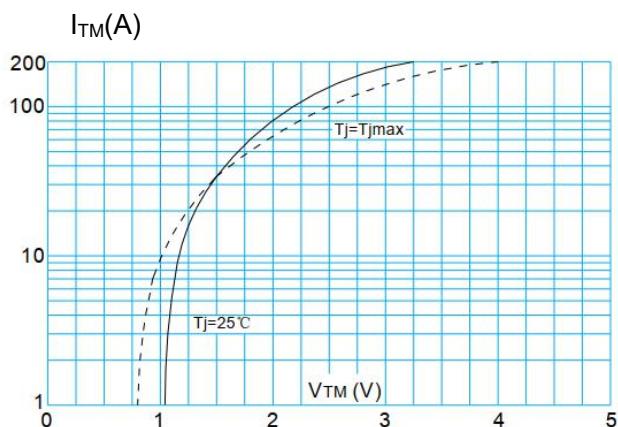
**FIG.5:** Non-repetitive surge peak on-state current for a sinusoidal pulse with width  $t_p < 20\text{ms}$ , and corresponding value of  $I^2t$  ( $I - II - III : dI/dt < 50\text{A}/\mu\text{s}; IV : dI/dt < 10\text{A}/\mu\text{s}$ )



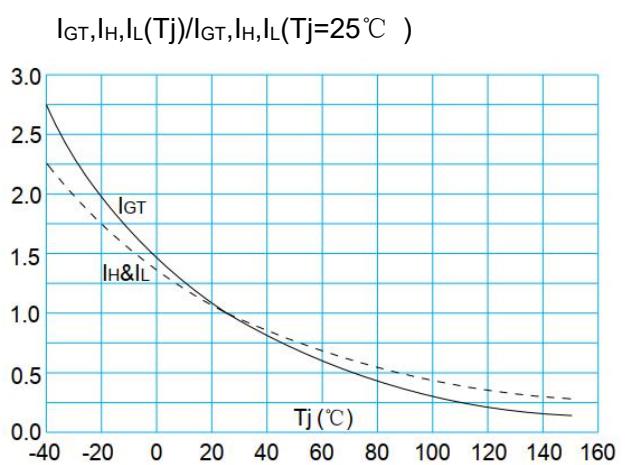
**FIG.2:** RMS on-state current versus case temperature



**FIG.4:** On-state characteristics (maximum values)



**FIG.6:** Relative variations of gate trigger current, holding current and latching current versus junction temperature





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